Form PTO-1449 (Modified)	Atty Docket No.: 03692.P054D2	Serial No.: 10/647,925
List of Patents and Publications Statement (Use several sheets if necessary)	Applicants: Disney, D.	
	Filing Date: August 26,2003	

REFERENCE DESIGNATION | **U.S. PATENT DOCUMENTS**

Exam. Initial		Date	Document Number	Name	Class	Sub-Class	Filing Date

FOREIGN PATENT DOCUMENTS

No.		Document No.	Date	Country	Name	Class	Sub-Class	Trans-lation
Loke		JP 6-224426	08/12/94	Japan	Uno			English
Loke		DE 43 09 764	09/29/94	Germany	Tihanyi, et al.			
Loke		JP 56-38867	04/14/81	Japan	Okabe, T., et al.			English
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Loke		JP 57-12557	01/22/82	Japan	Tanaka, et al.			English
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Loke		JP 60-64471	04/13/85	Japan	Saitou, M.			

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Loke		"Theory of Semiconductor Superjunction Devices," T. Fujuhana, Japanese Journal of Applied Physics, Part 1, October 1997, Vol. 36, No. 10, Pages 6254-6262.

Examiner	*Date Considered*
Loke	6/29/04

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Loke		"High Performance 600 V Smart Power Technology Based on Thin Layer Silicon-on-Insulator," T. Letavic, et al., Phillips Electronics North America Corp., 4 Pages.
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Loke		"Modeling Optimization of Lateral High Voltage IC Devices to Minimize 3-D Effects," H. Yilmaz, R&D Engineering, GE Corp., NC, Pages 290-297.

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